

Supporting Information

Extremely Low Thermal Conductivity and High Thermoelectric Performance in Liquid-like $\text{Cu}_2\text{Se}_{1-x}\text{S}_x$ Polymorph Materials

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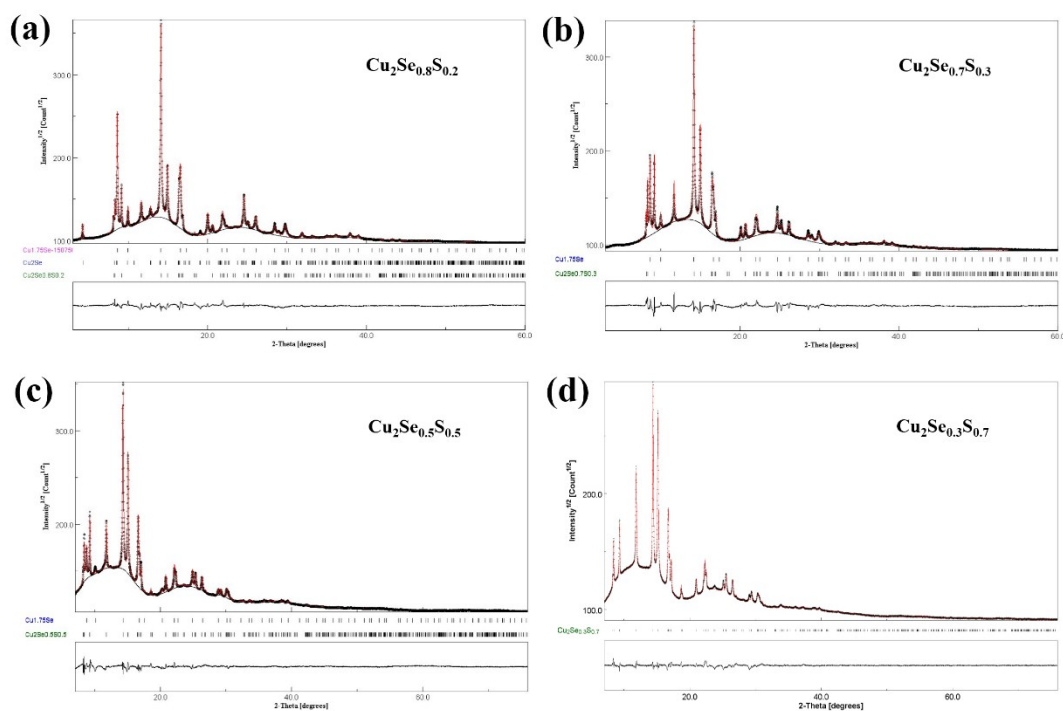


Fig. S1. Synchrotron Rietveld refinements for $\text{Cu}_2\text{Se}_{1-x}\text{S}_x$ ($x = 0.2, 0.3, 0.5$ and 0.7) samples.

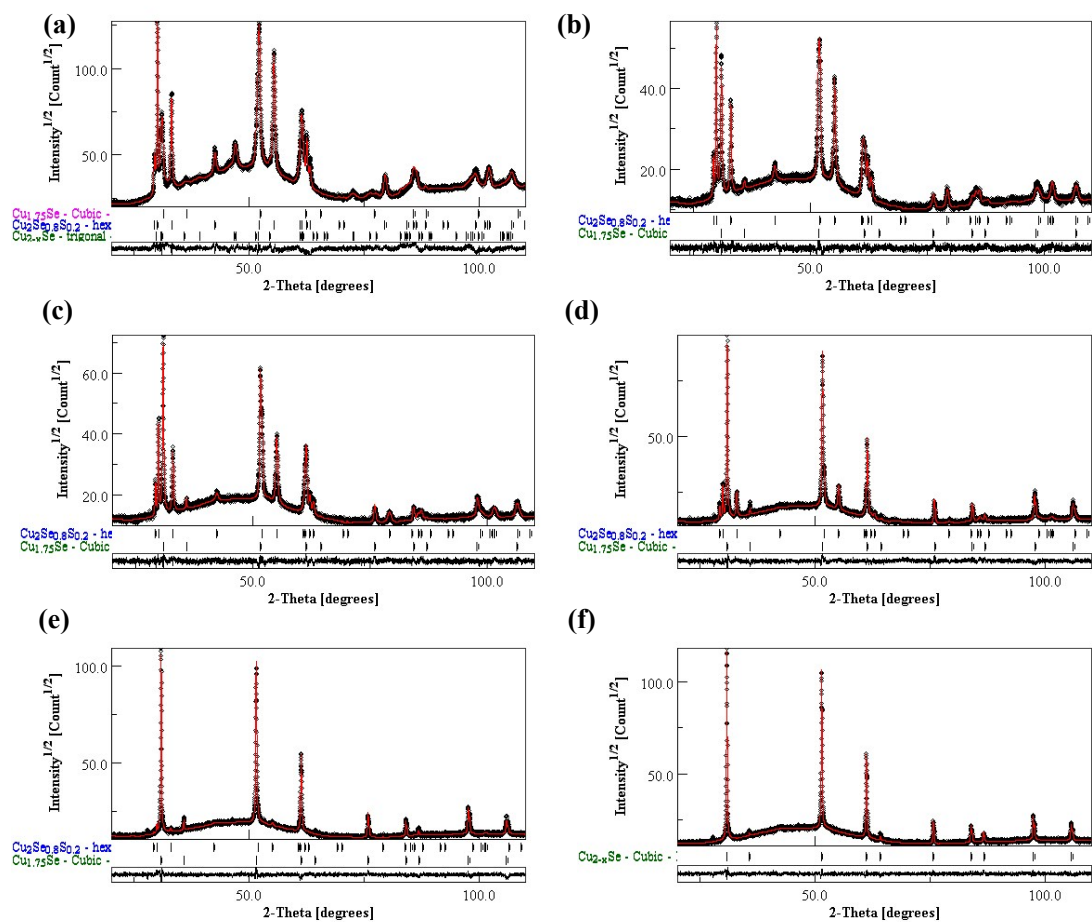


Fig. S2. Rietveld refinements for PXRD with Co- K_{α} source for $\text{Cu}_2\text{Se}_{0.8}\text{S}_{0.2}$, at (a) RT, (b) 400 K, (c) 450 K, (d) 475 K, (e) 500 K, and (f) 600 K. During refinement, a March-Dollase model for slight preferred orientation for (001) peaks was used for the hexagonal phase.

Table S1. Detailed Rietveld analysis for the PXRD results shown in Fig. S2.

Temp.			RT	400 K	450 K	475 K	500 K	600 K		
	R _B	(%)	4.35	5.19	5.17	5.60	5.26	4.74		
	R _{wp}	(%)	5.76	6.66	6.61	7.06	6.61	6.14		
	R _{exp}	(%)	2.65	6.42	6.16	6.20	6.14	5.77		
	χ ²		2.18	1.04	1.07	1.14	1.08	1.06		
Trigonal Cu₂Se_{0.8}S_{0.2}	<i>R</i> 3 <i>m</i>	a	(Å)	4.0863(3)	-	-	-	-		
		c	(Å)	20.268(2)	-	-	-	-		
	Se/S	Ratio		80/20	-	-	-	-	-	
		x		2/3	-	-	-	-	-	
		y		1/3	-	-	-	-	-	
		z		0.5797(2)	-	-	-	-	-	
		U _{iso}	(Å ²)	0.025(1)	-	-	-	-	-	
	Cu2	x		0.6917(3)	-	-	-	-	-	
		z		0.002(3)	-	-	-	-	-	
		U _{iso}	(Å ²)	0.6008(8)	-	-	-	-	-	
	Cu1a	x		1/3	-	-	-	-	-	
		y		2/3	-	-	-	-	-	
		z		0.7768(4)	-	-	-	-	-	
		U _{iso}	(Å ²)	0.008(2)	-	-	-	-	-	
		Occ.		0.620(7)	-	-	-	-	-	
	Cu1b	z		0.7169(7)	-	-	-	-	-	
	Hexagonal Cu₂Se_{0.8}S_{0.2}	<i>P</i> 6 ₃ / <i>mmc</i> <i>a</i>	a	(Å)	4.0702(1)	4.0794(1)	4.0863(1)	4.0889(2)	4.090(1)	-
			c	(Å)	6.8974(2)	6.9220(3)	6.9284(2)	6.9305(3)	6.936(1)	-
		Se/S	Ratio		80/20	80/20	80/20	80/20	80/20	-
			x		2/3	2/3	2/3	2/3	2/3	-
y				1/3	1/3	1/3	1/3	1/3	-	
z				3/4	3/4	3/4	3/4	3/4	-	
U _{iso}			(Å ²)	0.0227(7)	0.0334(7)	0.0373(9)	0.031(2)	0.0376	-	
Cu1		x = y		0	0	0	0	0	-	
		z		¼	¼	¼	¼	¼	-	
		U _{iso}	(Å ²)	0.043(2)	0.042(2)	0.018(2)	0.024(6)	0.059	-	
		Occ.		0.735(6)	0.675(6)	0.632(6)	0.59(2)	0.695	-	

Cu2	x		0.3945(9)	0.3985(7)	0.4039(6)	0.408(2)	-	-	
	z		0.5671(3)	0.5713(3)	0.5712(4)	0.5803(8)	-	-	
	U _{iso}	(Å ²)	0.041(3)	0.042(2)	0.018(2)	0.024(6)	-	-	
	Occ.		0.197(2)	0.182(2)	0.182(2)	0.170(5)	-	-	
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Cubic	<i>Fm</i> $\bar{3}$ <i>m</i>	a	(Å)	5.730(3)	5.7959(2)	5.8121(2)	5.81899(8)	5.82296(6)	5.83337(6)
Cu₂Se_{0.8}S_{0.2}									
Se/S	Ratio			80/20	80/20	80/20	80/20	80/20	80/20
	x = y = z			0	0	0	0	0	0
	U _{iso}	(Å ²)		0.028	0.045(2)	0.061(1)	0.0468(6)	0.0461(5)	0.0498(4)
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Cu1	x = y = z	¼	¼	¼	¼	¼	¼	¼	¼
	U _{iso}	(Å ²)		0.0412	0.12(1)	0.068(2)	0.073(4)	0.063(3)	0.061(3)
	Occ.			0.594	0.73(9)	0.424(5)	0.41(3)	0.36(2)	0.29(2)
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Cu2	x = y = z			0.326	0.33(2)	0.375(2)	0.320(3)	0.318(1)	0.317(1)
	Occ.			0.0714	0.03(2)	0.025(1)	0.093(5)	0.108(3)	0.111(3)

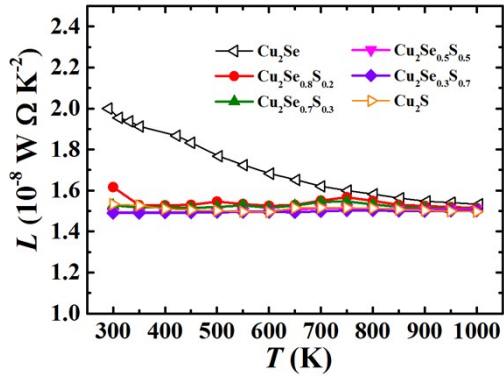


Fig. S3. Temperature dependence of Lorenz number for Cu₂Se_{1-x}S_x (x= 0, 0.2, 0.3, 0.5, 0.7, and 1.0) samples.

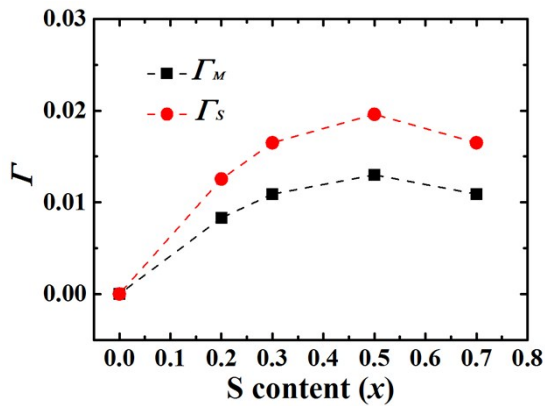


Fig. S4. Mass fluctuation scattering parameter Γ_M and strain field fluctuation scattering parameter

T_S as a function of the S-alloying content.

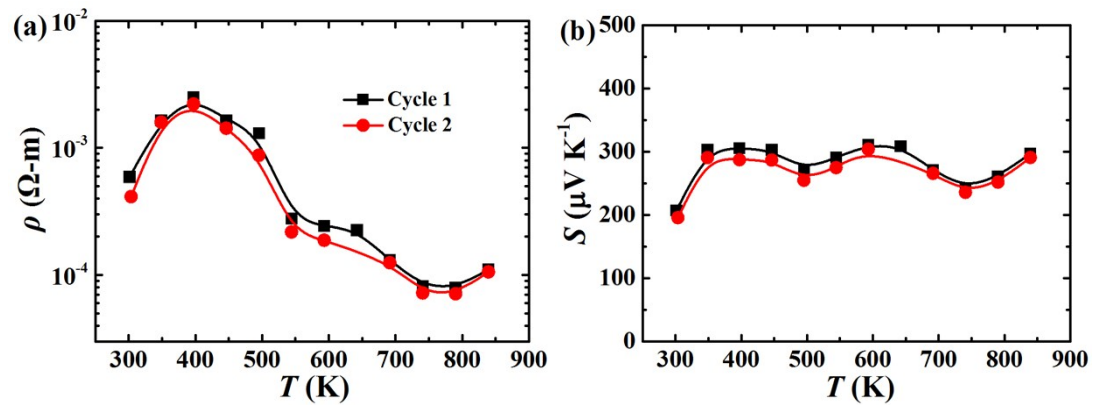


Fig. S5. Repeatability test on electronic transport properties in $\text{Cu}_2\text{Se}_{0.8}\text{S}_{0.2}$ sample.